

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

Attorney Docket Number	23-65037-01
Application Number	10/726,744
Filing Date	December 2, 2003
First Named Inventor	Larry C. Olsen
Art Unit	1753
Examiner Name	Anthony D. Fick

U.S. PATENT DOCUMENTS

Copies of U.S. Patent documents do not need to be provided, unless requested by the Patent and Trademark Office. For patents, provide the patent number and the issue date. For published U.S. applications, provide the publication number and the publication date. For unpublished pending patent applications, provide the application number and the filing date.

Examiner's Initials*	Cite No. (optional)	Number	Publication Date	Name of Applicant or Patentee
		3,648,470	3/1972	Schultz
		3,945,855	3/1976	Skrabek et al.
		4,677,416	6/1987	Nishimoto et al.
		4,940,976	7/1990	Gastouniotis et al.
		5,228,923	7/1993	Hed
		5,505,835	4/1996	Sakaue et al.
		6,162,985	12/2000	Parise
		6,215,580	4/2001	Kouta
		2003/0140957	7/2003	Akiba
		2004/0094192	5/2004	Luo
		2004/0242169	12/2004	Albsmeier et al.

FOREIGN PATENT DOCUMENTS

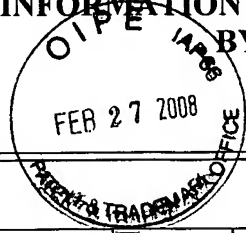
Examiner's Initials*	Cite No. (optional)	Country	Number	Publication Date	Name of Applicant or Patentee
		EPC	0408572A1	8/1989	
		EPC	0408572A0	No date	
		EPC	0408572B1	2/1993	
		GB	1381001	1/1975	

EXAMINER
SIGNATURE:

DATE
CONSIDERED:

* Examiner: Initial if reference considered, whether or not in conformance with MPEP 609. Draw line through cite if not in conformance and not considered. Include copy of this form with next communication to applicant.

**INFORMATION DISCLOSURE STATEMENT
BY APPLICANT**



Attorney Docket Number	23-65037-01
Application Number	10/726,744
Filing Date	December 2, 2003
First Named Inventor	Larry C. Olsen
Art Unit	1753
Examiner Name	Anthony D. Fick

FOREIGN PATENT DOCUMENTS

Examiner's Initials*	Cite No. (optional)	Country	Number	Publication Date	Name of Applicant or Patentee
		JP	61259580	11/1986	
		RU	2113035	8/1990	
		WIPO	89/07836	8/1989	

OTHER DOCUMENTS

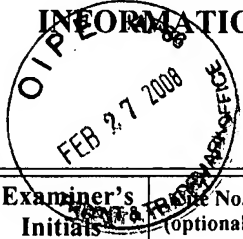
Examiner's Initials*	Cite No. (optional)	
		Abrikosov, N Kh, et al., "Phase transitions and electrophysical properties of the solid solutions based on GeTe at the cross-section of GeTe-AgSbTe ₂ ," <i>Izvestiya Akademii Nauk SSSR, Neoorganicheskie Materialy</i> , Abstract Only, Vol. 20, No. 1, pp. 55-59 (1984).
		Androulakis et al., "Nanostructuring and its Influence on the Thermoelectric Properties of the AgSbTe ₂ -SnTe Quaternary System," <i>Materials Research Society Symposium Proceedings</i> , Vol. 886, Abstract Only, 1 page (2006).
		Decheva, S.K., "Studies on the Thermoelectric Characteristics of Cold-Pressed Materials of the Type of (GeTe) _x --(AgSbTe ₂) (1--x)," <i>Bulgarian Journal of Physics</i> , Abstract Only, Vol. 6, No. 2, pp. 194-200 (1979).
		DeSteele, J. G. et al., "Technology Development: Wireless Sensors and Controls BT0201," Excerpt from Statement of Work from PNNL to U.S. Department of Energy, Building Technologies Program, 31 pages (September 2004).
		DeSteele, J. G., "Thermoelectric Ambient Energy Harvester," a White Paper for the Defense Logistics Agency, pp. 1-4 (undated).
		Martin, P. M. et al., "Si/SiGe Superlattices For Thermoelectric Applications" <i>Proceedings of the 46th Annual Technical Conference of the Society of Vacuum Coaters</i> , pp. 126-129 (2003).
		Martin, P. M. et al., "Scale Up of Si/ Si _{0.8} Ge _{0.2} and B ₄ C/B ₉ C Superlattices for Harvesting of Waste Heat," <i>Proceedings of DEER</i> , 6 pages (2003).
		Martin, P. M. et al., "Recent Advances in Scale Up of Si/SiGe Superlattices for Thermoelectric Applications," Abstract Only, presented at the Functional Coating and Surface Engineering Conference 2003, Montreal, Canada, 3 pages (June 4-7, 2003).
		Martin, P. M. et al., "Nanostructured multilayer B ₄ C/B ₉ C and Si/Si _{0.8} Ge _{0.2} films for advanced detector and thermoelectric applications," <i>Proceedings of 2004 AIMCAL Conference</i> , 7 pages (2004).

EXAMINER
SIGNATURE:

DATE
CONSIDERED:

* Examiner: Initial if reference considered, whether or not in conformance with MPEP 609. Draw line through cite if not in conformance and not considered. Include copy of this form with next communication to applicant.

**INFORMATION DISCLOSURE STATEMENT
BY APPLICANT**



Attorney Docket Number	23-65037-01
Application Number	10/726,744
Filing Date	December 2, 2003
First Named Inventor	Larry C. Olsen
Art Unit	1753
Examiner Name	Anthony D. Fick

Examiner's Initials
Examiner's Name No. (optional)

OTHER DOCUMENTS

	Martin, P. M. et al., "Superlattice Coatings for Device, Structural and Protective Applications," <i>Proceedings of AIMCAL 2006 Fall Technical Conference</i> , invited, 10 pages (2006).
	Martin, P. M. et al., "Recent advances in magnetron sputtered superlattice and quantum well structures," <i>Proceedings of SPIE</i> , Vol. 6403, pp. 640310-10 to 640310-11 (2006).
	Martin, P. M. et al., "Magnetron-Sputtered Nanolaminate and Superlattice Coatings," <i>Proceedings of SPIE</i> , Vol. 6403, pp. 640310-1 to 640310-9 (2006).
	Office action from the U.S. Patent and Trademark Office in U.S. Patent Application No. 11/004,611, dated January 7, 2008.
	Office action from the U.S. Patent and Trademark Office in U.S. Patent Application No. 10/727,062, dated June 14, 2007.
	Plachkova, S.K. et al., "Materials for Thermoelectric Application Based on the System GeTe-AgBiTe ₂ ," <i>Physica Status Solidi (A)</i> , Abstract Only, Vol. 184, Issue 1, pp. 195-200 (March 2001).
	Plachkova, S.K., "Thermoelectric figure of merit of the system (GeTe) _{1-x} (AgSbTe ₂) _x ," <i>Phys. Stat. Sol (A)</i> , Abstract Only, Vol. 83, No. 1, pp. 349-356 (1984).
	Plachkova, S.K., "Thermoelectric Power in the System (GeTe) _{1-x} (AgSbTe ₂) _x ," <i>Phys. Status Solidi (A)</i> , Abstract Only, Vol. 80, No. 1, pp. K97-K100 (Nov. 16, 1983).
	Sharp, J. W., "Some Properties of GeTe-Based Thermoelectric Alloys," <i>IEEE 22nd International Conference on Thermoelectrics</i> , pp. 267-270 (2003).
	Yamanaka, S. et al., "Thermoelectric properties of Tl ₉ BiTe ₃ ," <i>Journal of Alloys and Compounds</i> , Vol. 352, pp. 275-278 (2003).

EXAMINER
SIGNATURE:

DATE
CONSIDERED:

* Examiner: Initial if reference considered, whether or not in conformance with MPEP 609. Draw line through cite if not in conformance and not considered. Include copy of this form with next communication to applicant.